



Features

- High Blocking Voltage with Low On-Resistance
- High Speed Switching with Low Capacitances
- Avalanche Ruggednes

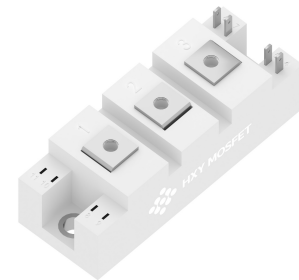
Applications

- Solar Inverters
- Switch Mode Power Supplies
- High Voltage DC-DC Converters
- Battery Chargers

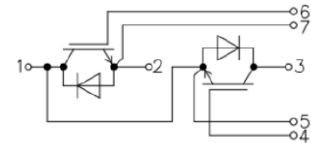


Package Marking and Ordering Information

Ordering Part Number	Package	Brand
C3M15120HB1	module-HB	HXY MOSFET



module-HB



Maximum Ratings ($T_c = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	1200	V
Continuous drain current $T_c = 25^\circ\text{C}$, $V_{GS} = 18\text{V}$ $T_c = 100^\circ\text{C}$, $V_{GS} = 18\text{V}$	I_D	117 84	A
Pulsed drain current ($T_c = 25^\circ\text{C}$, t_p limited by T_{jmax})	$I_{D\ pulse}$	250	A
Avalanche energy, single pulse (L=10mH)	E_{AS}	1200	mJ
Gate-Source voltage	V_{GS}	-4/+18	V
Gate-Source voltage (Absolute maximum values)	V_{GSmax}	-8/+22	V
Operating junction and storage temperature	T_j, T_{stg}	-55...+175	$^\circ\text{C}$

• Example of acceptable V_{GS} waveform





Electrical Characteristic (at $T_j = 25^\circ\text{C}$, unless otherwise specified)

Parameter	Symbol	Value			Unit	Test Condition	
		min.	typ.	max.			
Static Characteristic							
Drain-source breakdown voltage	V_{DSS}	1200	-	-	V	$V_{GS}=0V, I_D=100\mu A$	
Gate threshold voltage	$V_{GS(th)}$	2	3	4	V	$V_{DS}=V_{GS}, I_D=10mA$	
Zero gate voltage drain current	I_{DSS}	-	5	-	μA	$V_{DS}=1200V, V_{GS}=0V$ $T_C=25^\circ C$ $T_C=175^\circ C$	
		-	40	-			
Gate-source leakage current	I_{GSS}	-	-	100	nA	$V_{GS}=18V, V_{DS}=0V$	
Drain-source on-state resistance	$R_{DS(on)}$	-	15	23	m Ω	$V_{GS}=18V, I_D=33.4A,$ $T_J=25^\circ C$ $T_J=175^\circ C$	
		-	30	-			
Drain-source on-state resistance	$R_{DS(on)}$	-	20	30	m Ω	$V_{GS}=15V, I_D=33.4A,$ $T_J=25^\circ C$ $T_J=175^\circ C$	
		-	32	-			
Dynamic Characteristic							
Input Capacitance	C_{iss}	-	4837.8	-	pF	$V_{DS} = 1000V$ $V_{GS} = 0V$ $T_J = 25^\circ C$ $V_{AC}=25mV$ $f = 1MHz$	
Output Capacitance	C_{oss}	-	576.3	-			
Reverse Transfer Capacitance	C_{rss}	-	22.4	-			
Gate Total Charge	Q_G	-	189.5	-	nC	$V_{DS} = 800V, V_{GS} = -4/+18V, I_D = 80A, I_G=1mA$	
Gate-Source charge	Q_{gs}	-	40.9	-			
Gate-Drain charge	Q_{gd}	-	88.2	-			
Turn-On Switching Energy	E_{ON}	-	2.1	-	mJ	$V_{DD} = 800V, V_{GS} = -4/+18V, I_D = 80A, R_G = 5\Omega, L=100\mu H, T_J = 25^\circ C$	
Turn-Off Switching Energy	E_{OFF}	-	0.4	-			
Turn-on delay time	$t_{d(on)}$	-	62	-	ns		
Rise time	t_r	-	47.3	-			
Turn-off delay time	$t_{d(off)}$	-	86	-			
Fall time	t_f	-	15	-			
Gate resistance	R_G	-	0.87	-	Ω		$V_{AC} = 25mV, f=1MHz$



Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Body Diode Forward Voltage	V_{SD}		1.8		V	$V_{GS}=-4V, I_{SD}=40A,$ $T_J=25^{\circ}C$
			2.5			$V_{GS}=-4V, I_{SD}=40A,$ $T_J=175^{\circ}C$
Reverse Recovery Time	t_{rr}	-	245	-	ns	$V_R = 800V$ $I_D = 40A$ $di/dt = 1000A/\mu S$ $V_{GS} = -4V$ $T_J = 25^{\circ}C$
Reverse Recovery Charge	Q_{rr}	-	1291	-	nC	
Reverse Recovery Energy	E_{REC}	-	622	-	uJ	
Peak Reverse Recovery Current	I_{rrm}	-	14	-	A	
Charge Time	t_A	-	40	-	ns	
DisCharge Time	t_B	-	205	-	ns	

Thermal Resistance

Parameter	Symbol	Value	Unit
Thermal resistance, junction – case. Max	R_{thJC}	0.4	°C/W
Thermal resistance, junction – ambient. Max	R_{thJA}	40	



Typical Performance

Fig 1. Output Characteristic ($T_J = -55^\circ\text{C}$)

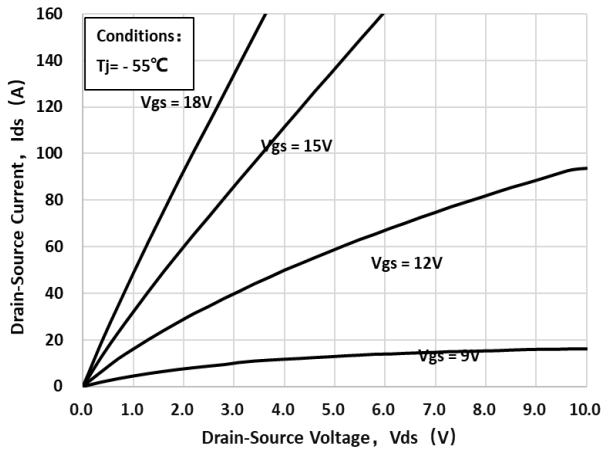


Fig 2. Output Characteristic ($T_J = 25^\circ\text{C}$)

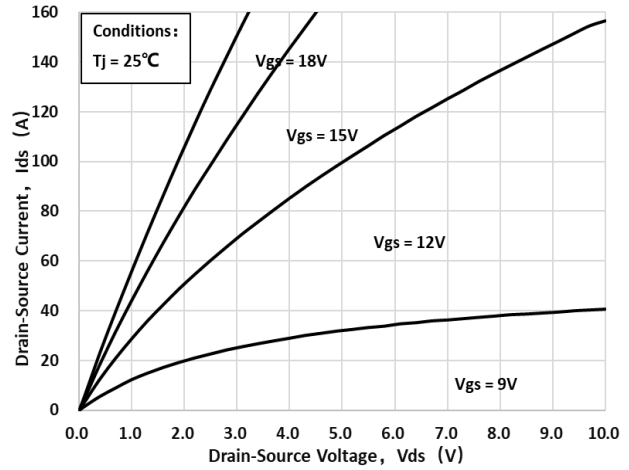


Fig 3. Output Characteristic ($T_J = 175^\circ\text{C}$)

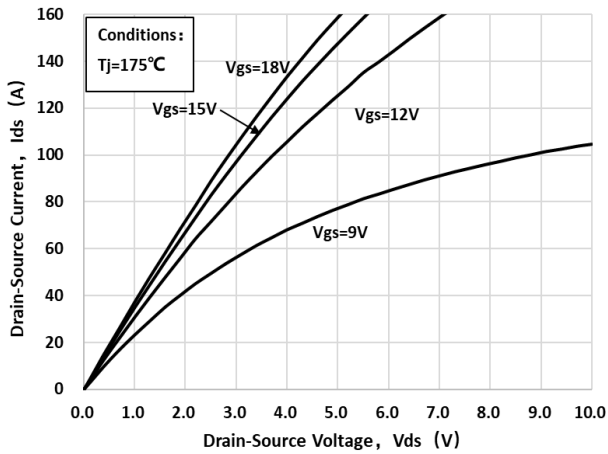


Fig 4: $R_{ds(on)}$ Vs I_{ds} Characteristic

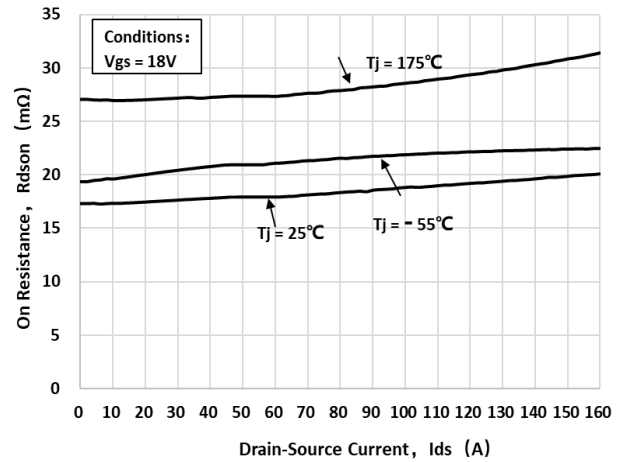


Fig 5: $R_{ds(on)}$ vs. Temperature

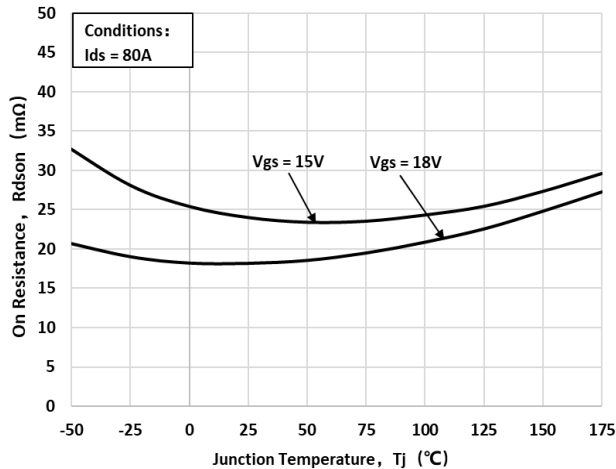


Fig 6: Transfer Characteristic

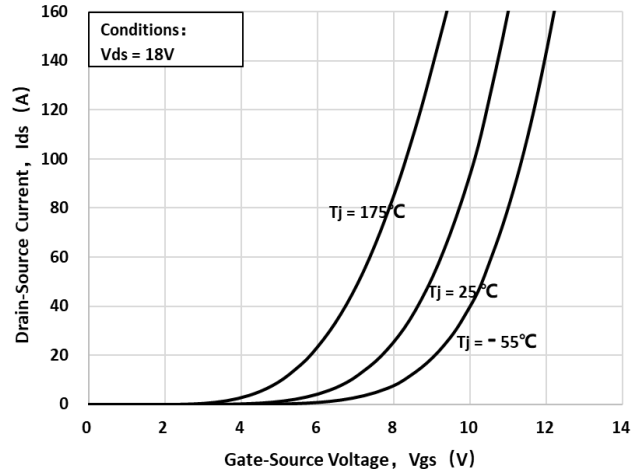




Fig 7: Body-diode Characteristic ($T_J = -55^\circ\text{C}$)

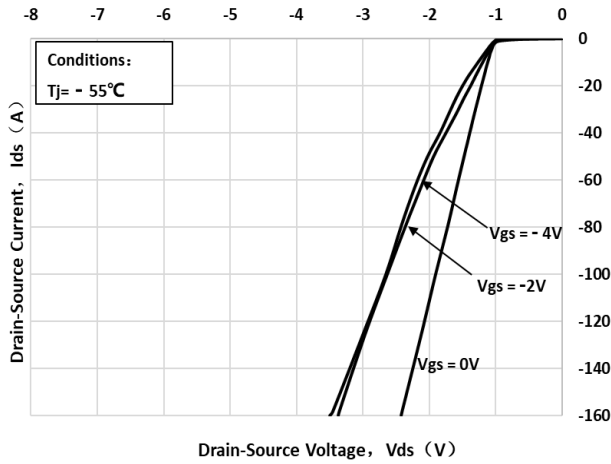


Fig 8: Body-diode Characteristic ($T_J = 25^\circ\text{C}$)

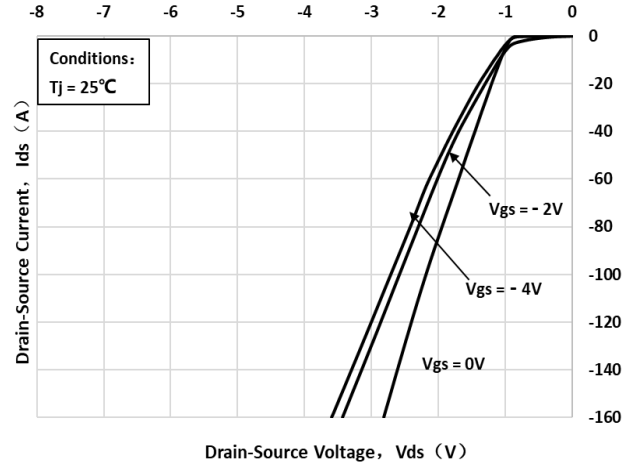


Fig 9: Body-diode Characteristic ($T_J = 175^\circ\text{C}$)

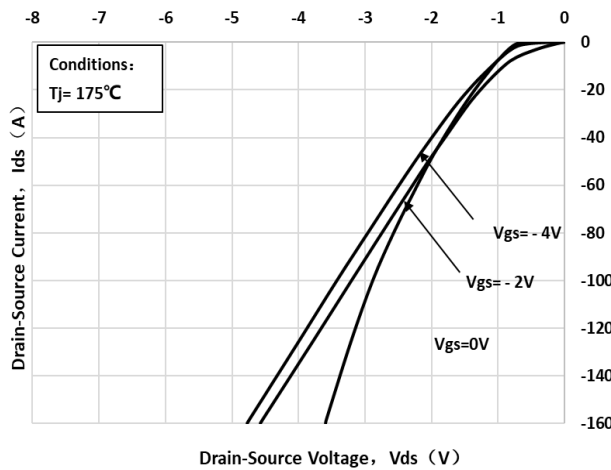


Fig 10: V_{TH} Vs T_J Temperature Characteristic

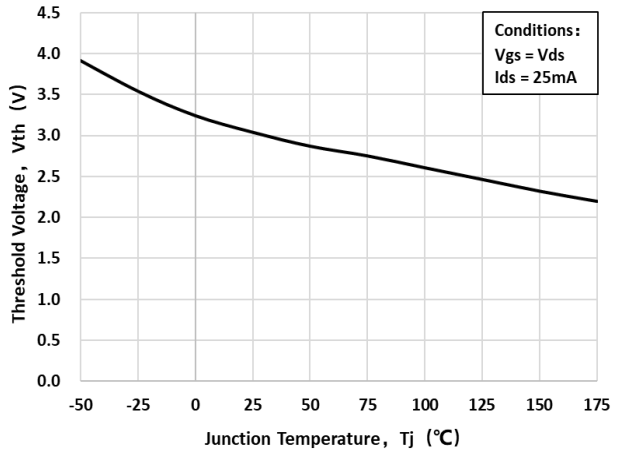


Fig 11: 3rd Quadrant Characteristic ($T_J = -55^\circ\text{C}$)

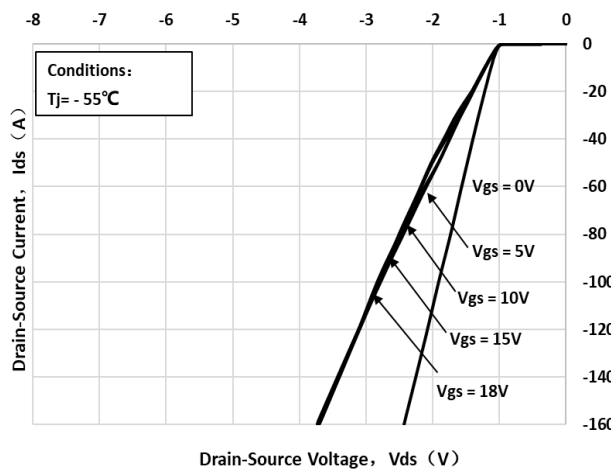


Fig 12: 3rd Quadrant Characteristic ($T_J = 25^\circ\text{C}$)

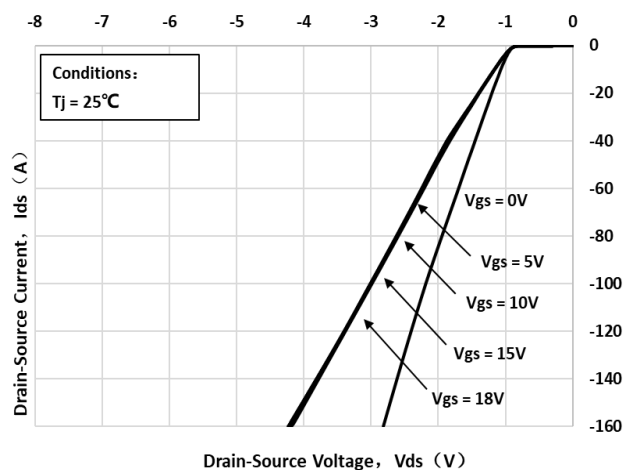




Fig 13: 3rd Quadrant Characteristic($T_J=175^\circ\text{C}$)

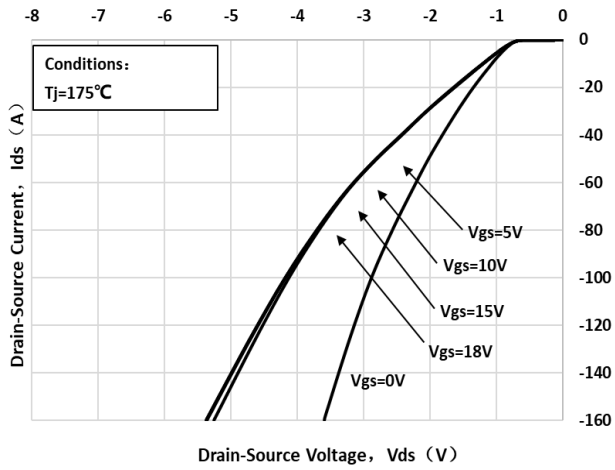


Fig 14: Gate Charge Characteristics

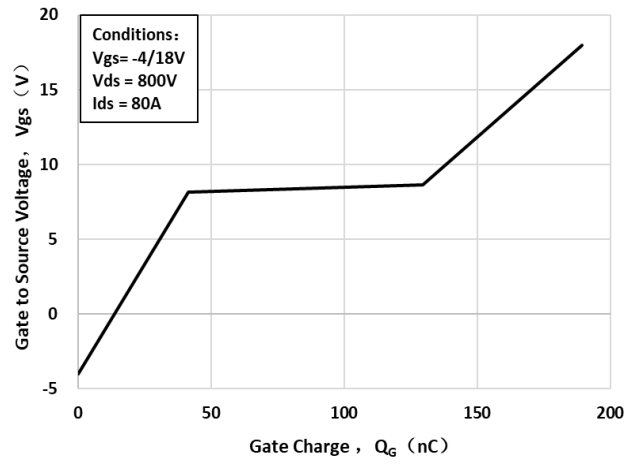
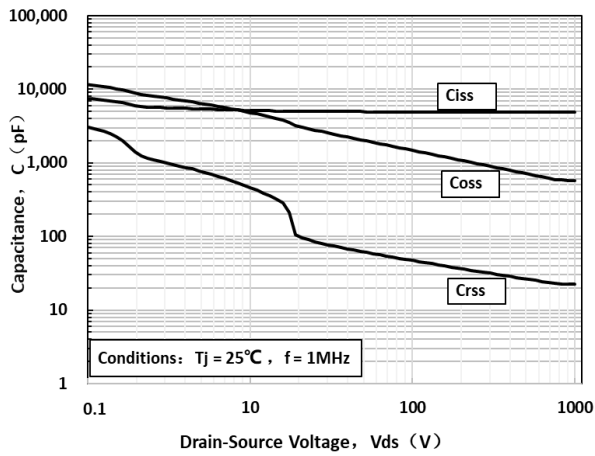


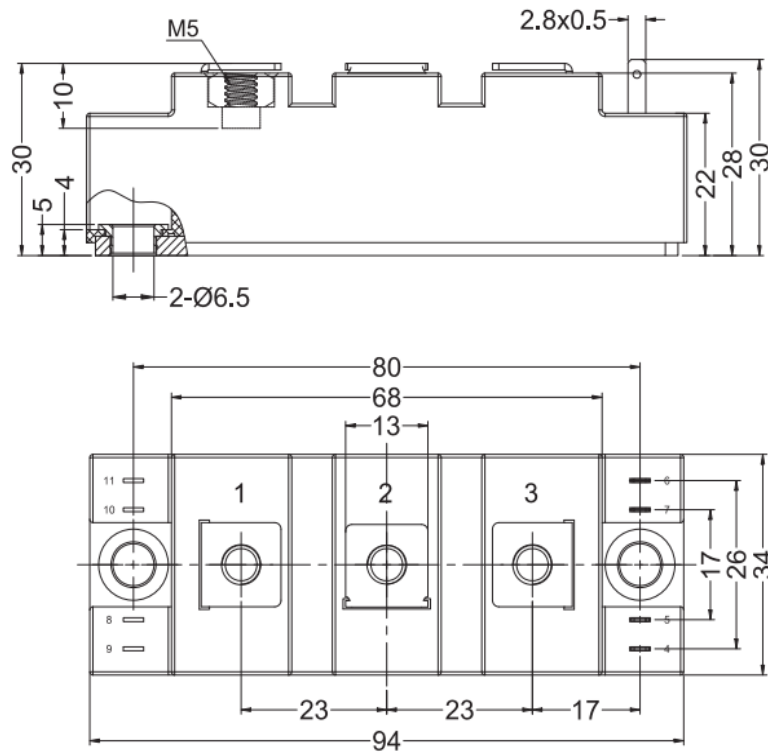
Fig 17: Capacitance Characteristics





Package Dimensions

Package module-HB





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